

INFORMATION DISCLOSURE
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APPLICANT

CHEN et al.

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10/730,382

GROUP

1756



(Use several sheets if necessary)

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*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
<i>h</i>	5,187,715	02/1993	Weisbuch et al.			
<i>ar</i>	5,281,840	01/1994	Sarma			
<i>ar</i>	6,005,707	12/1999	Berggren et al.			
<i>u</i>	4,253,728	09/2001 03/1981	Venkatesan et al.			
<i>h</i>	6,440,637	08/2002	Choi et al.			
<i>u</i>	6,819,845	11/2004	Lee et al.			
<i>u</i>	6,826,144	11/2004	Ichihara et al.			
<i>u</i>	6,927,002	08/2005	Hattori et al.			
<i>u</i>	2002/027647	03/2002	Cooper et al.			2002/0027647
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<i>u</i>	2004/0152011A1	08/2004	Chen et al. Chen et al.			

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DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
<i>h</i> WO 03/009058 A2	01/2003	PCT			

OTHER DOCUMENTS (including Author, Title, Date, Pertinent pages, etc.)

<i>h</i>	Nagase, et al., "Super-Resolution Effect of Semiconductor-Doped Glass," Jpn. J. Appl. Phys. Vol. 38 (1999), pp. 1665-1668, Part 1, No. 3B (03/1999)
<i>u</i>	Noharet, Bertrand, "Harnessing light with semiconductor Spatial Light Modulators," APERTUREN - SURFACES AND IMAGING, Vol. 1-2001, pp. 12-13, XP002363385 (2001)
<i>h</i>	Nomura, S. et al., "Clearly resolved exciton peaks in CdS _x Se _{1-x} microcrystallites by modulation spectroscopy", Sol. Stat. Comm., 73: 425-9 (1990).
<i>u</i>	Ooki, Hiroshi et al., "Experimental study on non-linear multiple exposure method," SPIE Vol. 3051, pp. 85-93, Santa Clara, California (March 12-14, 1997)
<i>u</i>	Shibuya, Masato et al., "Performance of Resolution Enhancement Technique Using Both Multiple Exposure and Nonlinear Resist," Jpn. J. Appl. Phys. Vol. 33 (1994), pp. 6874-6877, Part 1, No. 12B (12/1994)

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Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 809; draw line through citation if not in conformance and not considered. Initial this form with next communication to application.